

Atomic and molecular interactions.

Scanning probe microscopy.

Balázs Kiss



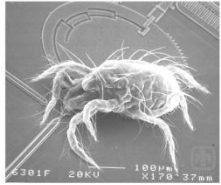
**Nanobiotechnology and Single Molecule
Research Group,
Department of Biophysics and Radiation Biology**

27. November 2013.

The Scale of Things – Nanometers and More



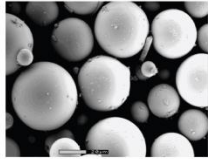
Things Natural



Dust mite
200 μm



Ant
~ 5 mm

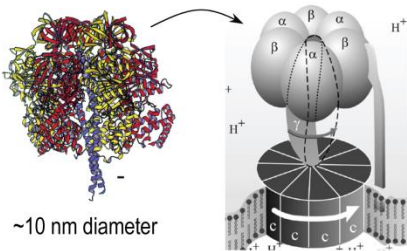
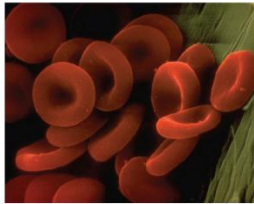


Fly ash
~ 10-20 μm

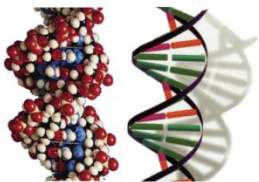


Human hair
~ 60-120 μm wide

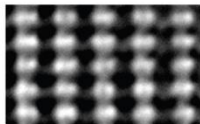
Red blood cells
(~7-8 μm)



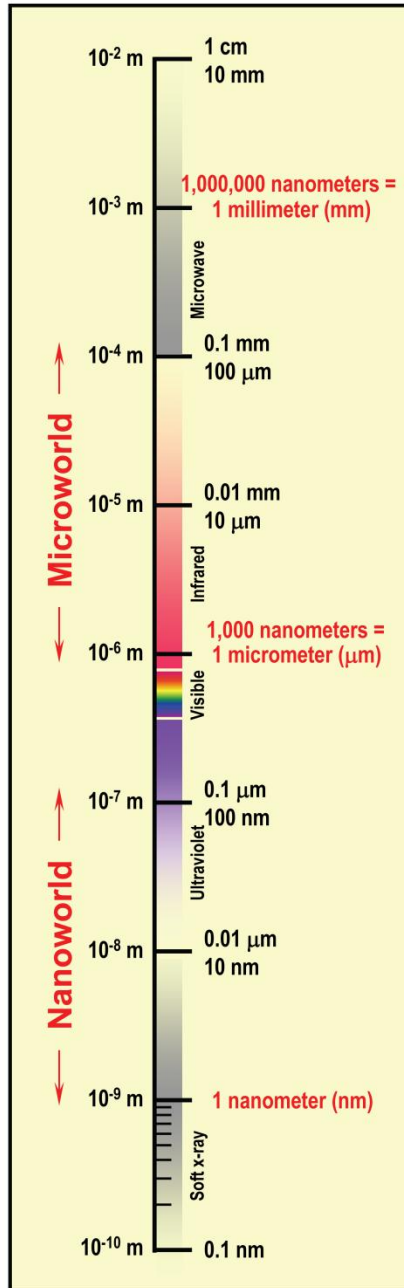
ATP synthase



DNA
~2-1/2 nm diameter



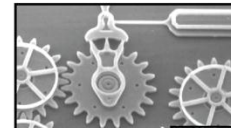
Atoms of silicon
spacing 0.078 nm



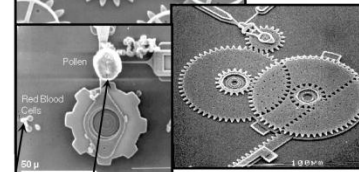
Things Manmade



Head of a pin
1-2 mm

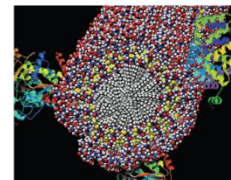
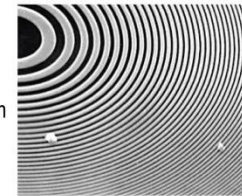


MicroElectroMechanical (MEMS) devices
10 -100 μm wide

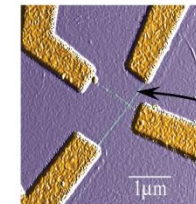


Pollen grain
Red blood cells

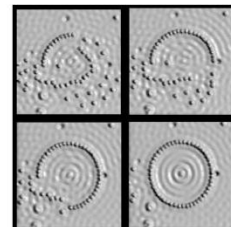
Zone plate x-ray "lens"
Outer ring spacing ~35 nm



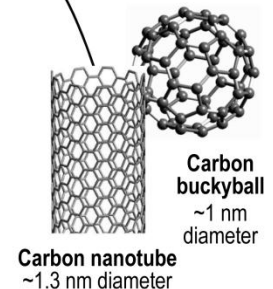
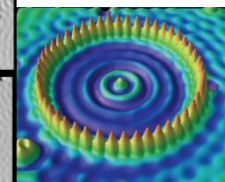
Self-assembled,
Nature-inspired structure
Many 10s of nm



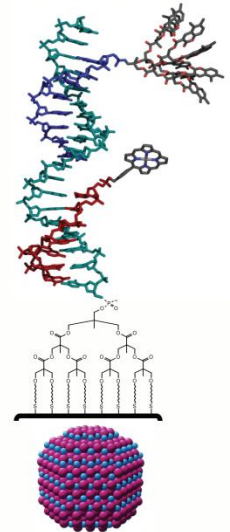
Nanotube electrode



Quantum corral of 48 iron atoms on copper surface
positioned one at a time with an STM tip
Corral diameter 14 nm



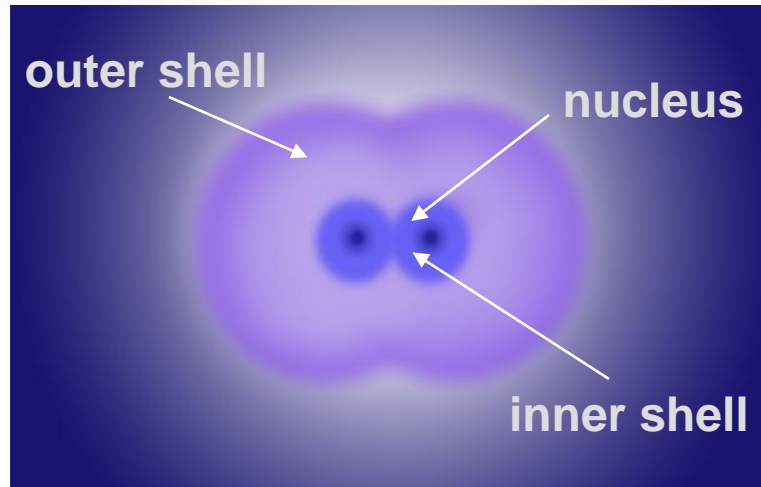
The Challenge



Fabricate and combine nanoscale building blocks to make useful devices, e.g., a photosynthetic reaction center with integral semiconductor storage.

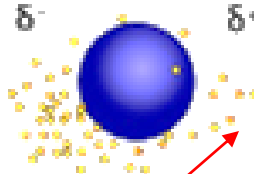
Atomic interactions

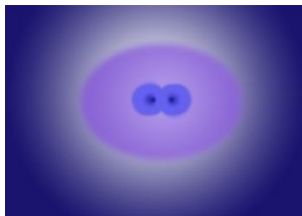
short range
interaction:
repulsion between
nuclei
(electron cloud overlap)



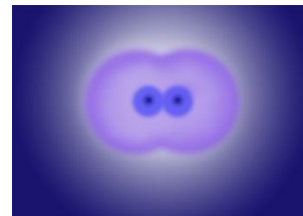
long range
interaction:
coulombic attraction

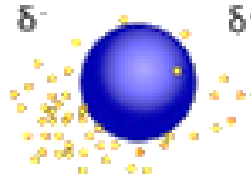
$$E_C = \frac{1}{4\pi\epsilon_0} \cdot \frac{Q_A Q_B}{r}$$

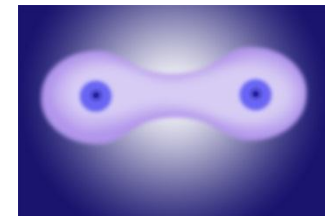

repulsion
(inner shells and nuclei)



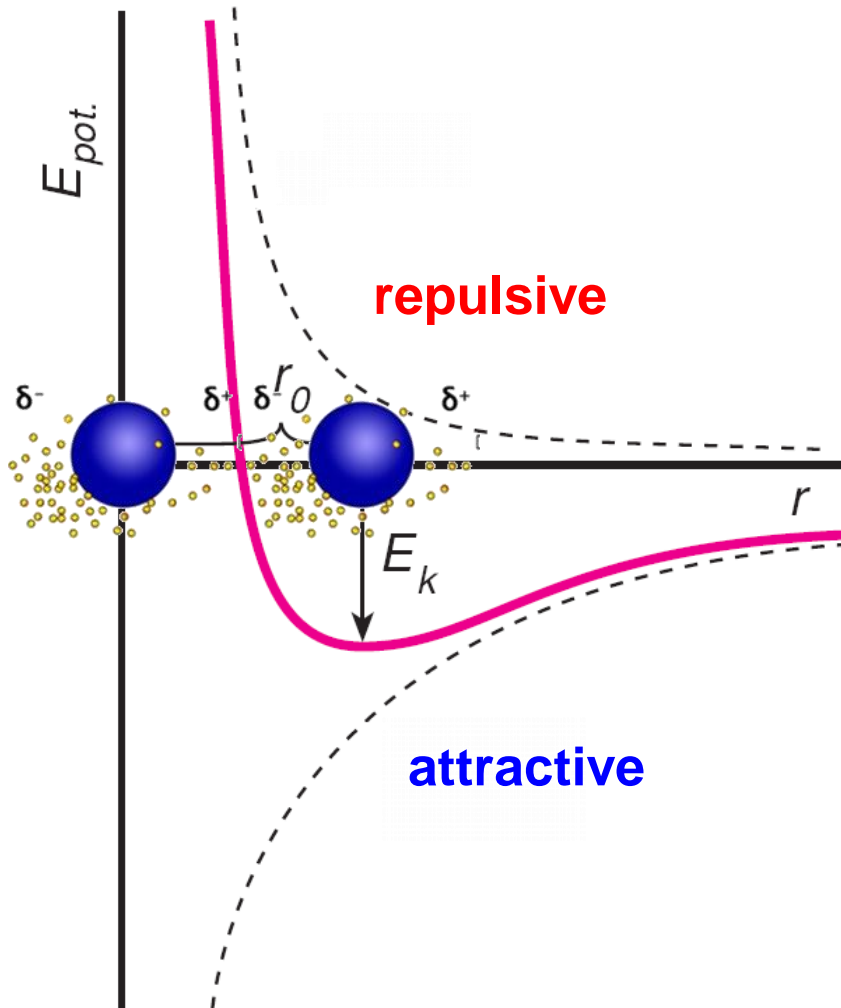
equilibrium
attraction = repulsion




attraction
(outer shells)



Atomic interactions



$$E_{pot} = E_{attraction} + E_{repulsion}$$

$$E_{pot} = -\frac{A}{r^n} + \frac{B}{r^m}$$

A, B: interaction-specific constants
(atom-dependent)

n (attraction) < m (repulsion)

r_0 : binding distance

E_k : binding energy

Primary bonds

2-6 eV/bond

intramolecular

intermolecular

~100 kJ/mol

strong

weak

0.01-0.1 eV/bond

primary

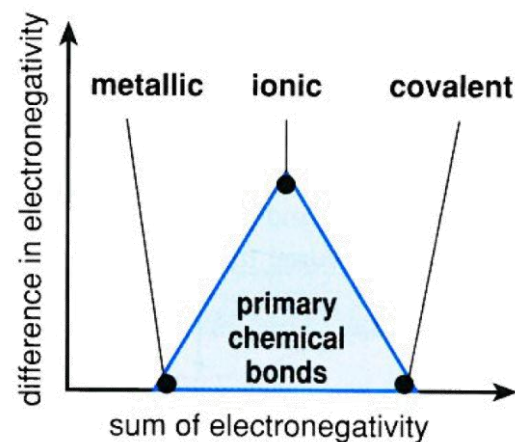
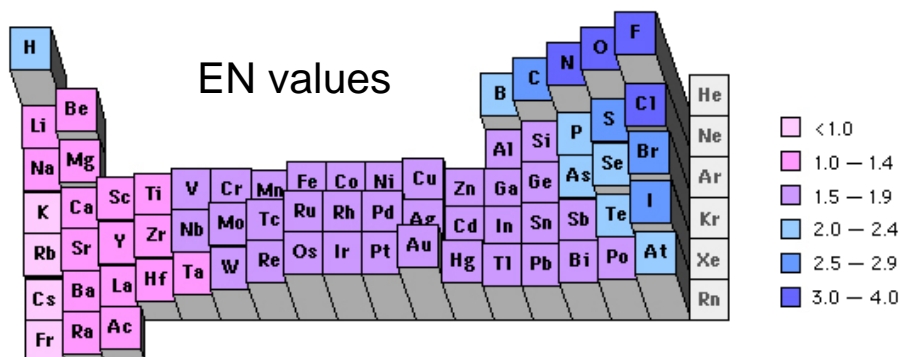
secondary

- **covalent:** common electron state around the participating nuclei
- **(metallic bond:** multi-atomic system)
- **electrostatic**
 - **ionic bond:** Coulomb-forces between ions
 - **dipole type charge distribution**

**type depends
from
electronegativity**

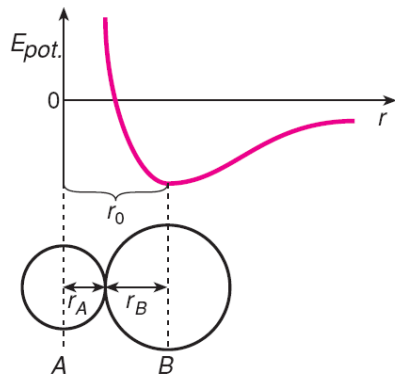
$$EN = (E_i + E_{ea})/2$$

(Mulliken)

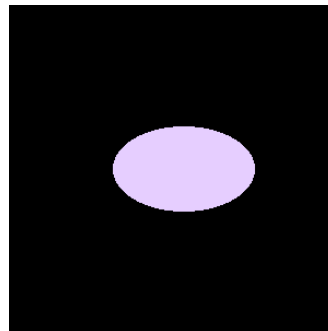


Secondary bonds 1

- **Van der Waals:** between atoms without permanent dipole moment (apolar)
 - temporarily created dipole interacts with an apolar molecule or atom thus converting it into a dipole (**induced dipole**)
- **Van der Waals radius:** $r_0 = r_A + r_B$



fluctuation



ion-dipole



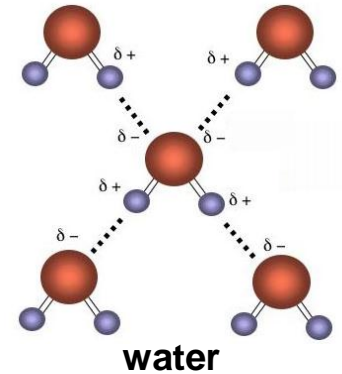
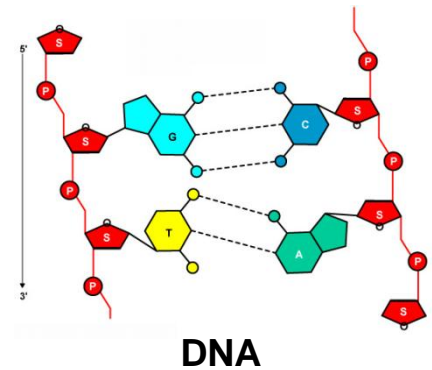
induced dipole



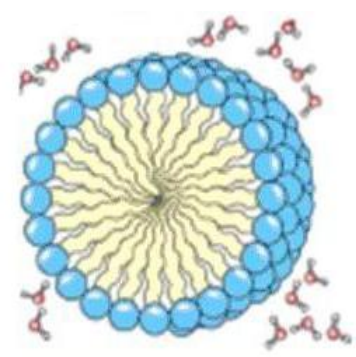
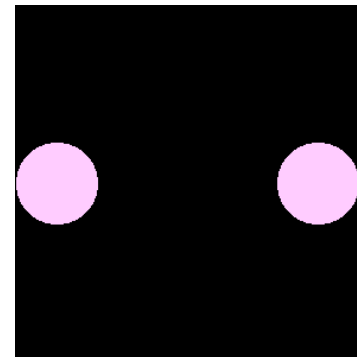
Interaction	Distance dependence of E_{pot}	Average binding energy (eV)
Ion-dipole	$1/r^2$	0.1-0.2
Dipole-dipole	$1/r^3$	0.02
Dispersion	$1/r^6$	0.02
Dipole-induced dipole	$1/r^6$	0.01

Secondary bonds 2

- **H-bond:** the H-atom interbridges 2 other atoms (F, O, N) of high electronegativity
 - $r \sim 0.23\text{-}0.35 \text{ nm}$
 - $E \sim 0.2 \text{ eV}$



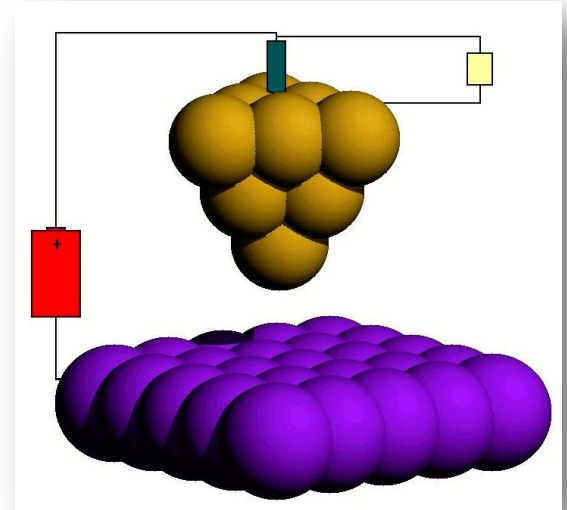
- **hydrophobic interaction:** weak Van der Waals interaction, but thermal motion ($kT \sim 0.025 \text{ eV}$) would disrupt the system
 - ordered water molecules exclude the apolar structures (minimized contact surface)



Scanning Probe Microscopy- history

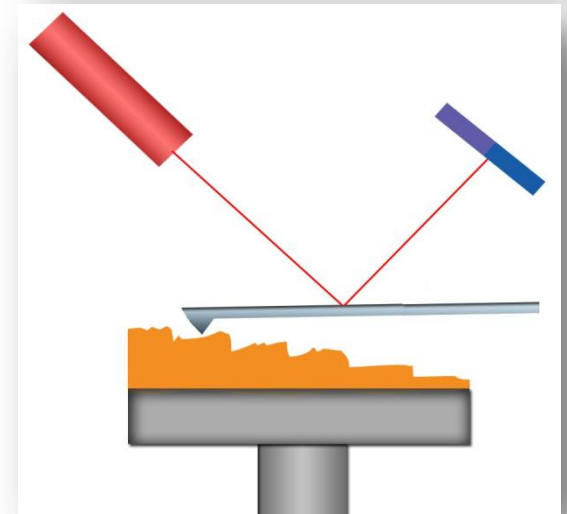
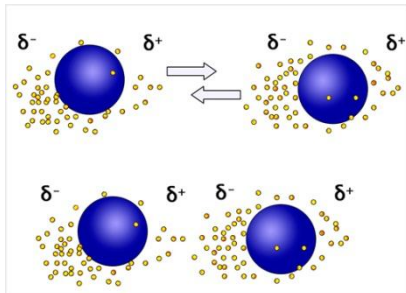
1981: Binning, Rohrer – IBM

- scanning tunneling microscopy



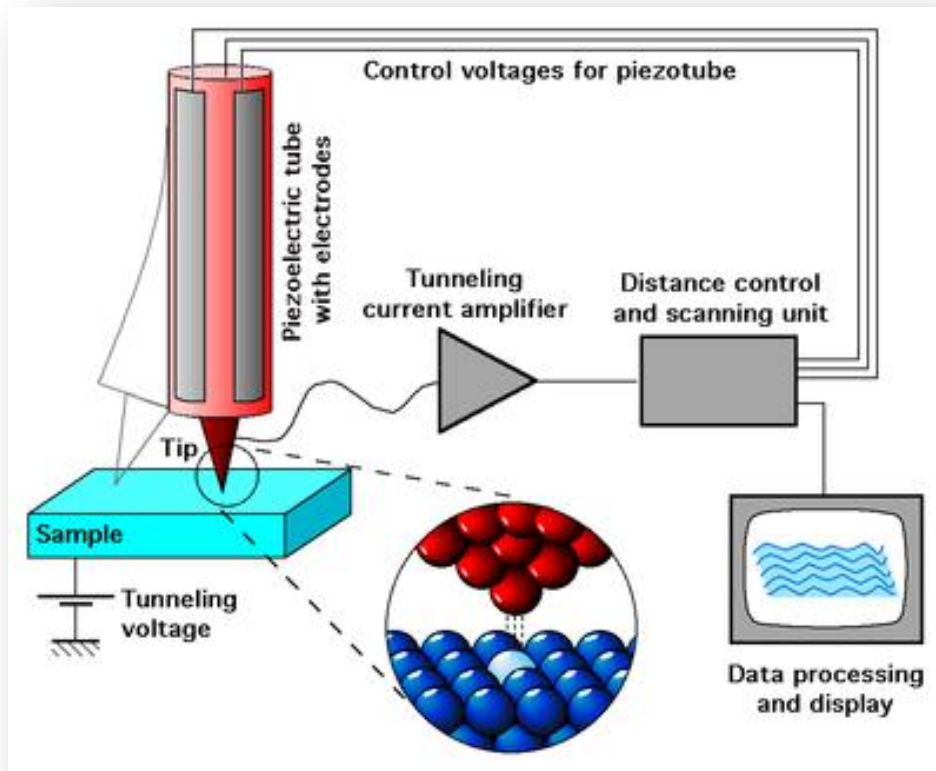
1986: Binning, Quate

- atomic force microscopy



Scanning Tunneling Microscopy

electron tunnelling: measurable electrical currents (I) between two conductors separated by a sufficiently thin uniform insulator



$$I \sim e^{-\kappa z}$$

z : distance (Z-axis)

κ : $2,2 \text{ \AA}^{-1}$

$I \sim \text{nA}$

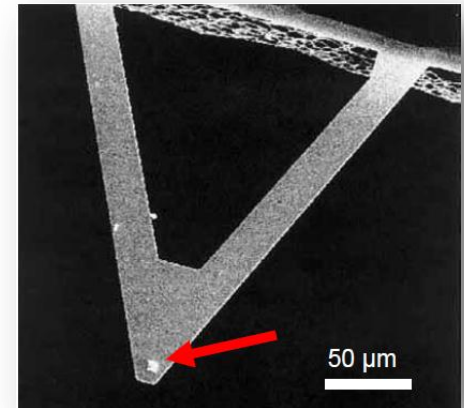
Atomic Force Microscopy

aim: to get rid of lens / optics: light is not favorable in direct imaging
(Abbe's Principle limits the resolution)

- „do it yourself”:

- **thin, soft probe („point detector”)**

to measure Van der Waals interactions between tip and surface



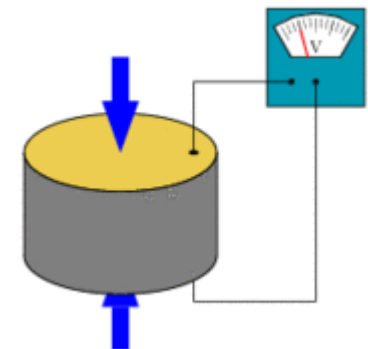
- **smooth surface (mica)**

clean, atomic layer

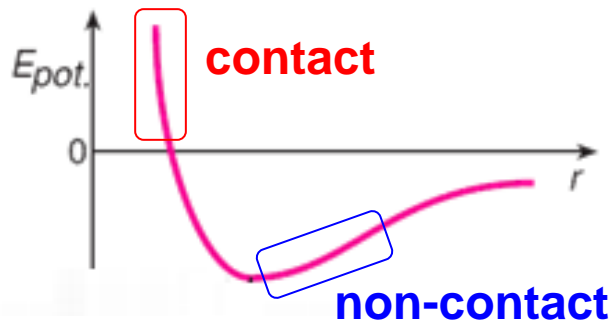
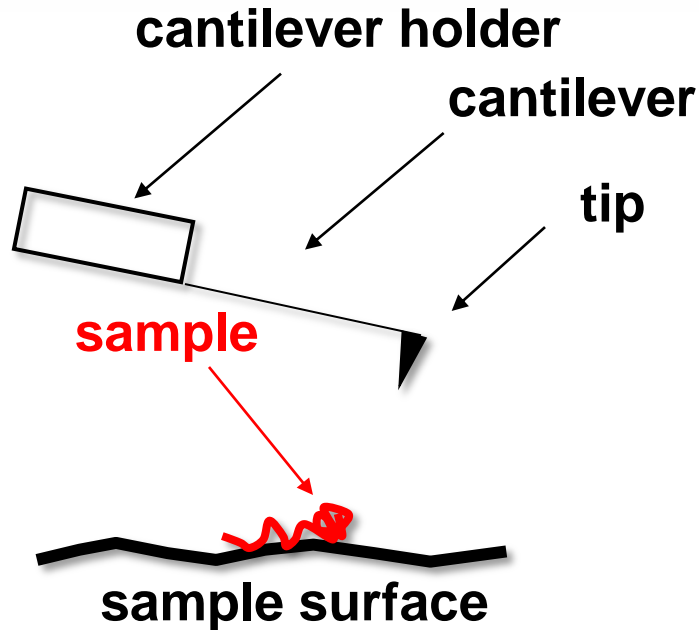


- **stage: X/Y/Z piezoelectric actuators**

translational motion in atomic steps: step size $\sim 1\text{\AA}$ (angstrom) = 0.1 nm



Atomic force microscope (AFM)



operating modes:

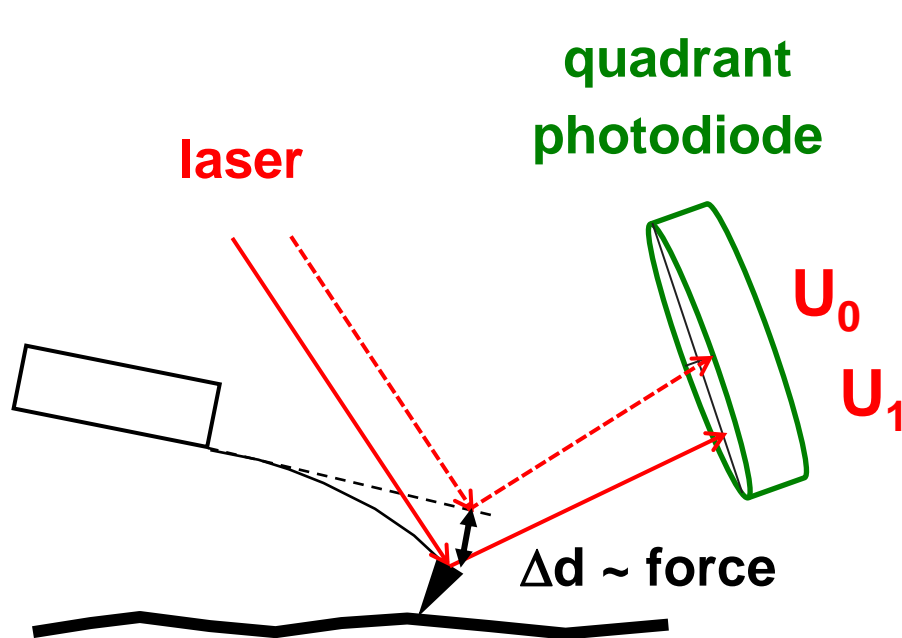
- **contact**: the tip touches the surface: cantilever deflection relates to the surface topography
- **non-contact**: the tip is being oscillated without contact with the surface: amplitude and resonant frequency changes
- **oscillating**: the cantilever is being oscillated near its resonant frequency

Atomic force microscope (AFM)

<http://personal.ph.surrey.ac.uk/~phs1ad/MAT/MAT/Scanning%20Probe%20Micorscopies/Atomic%20Force%20Microscopy/modes%5B1%5D.swf>

Working principle of AFM 1

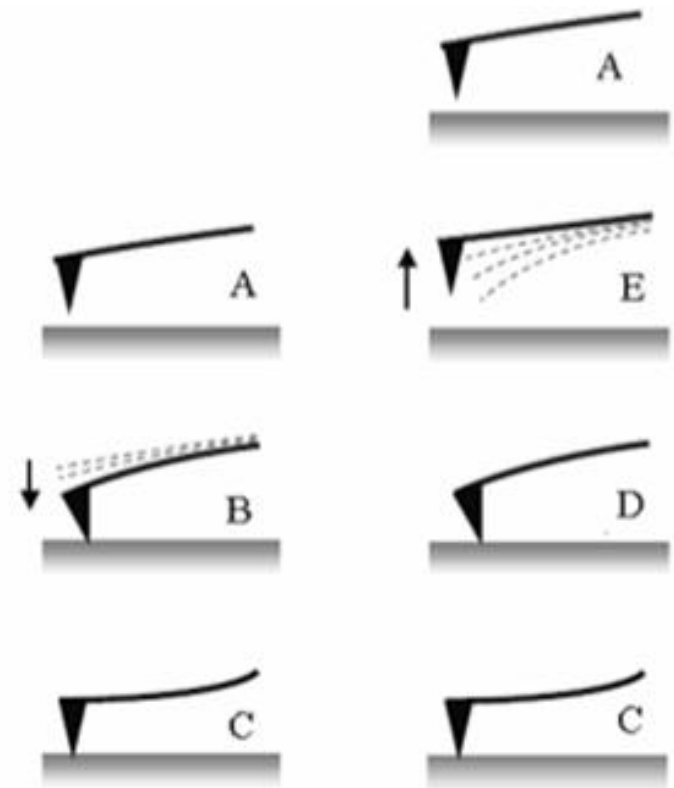
contact mode



$$F = \text{force} = D \Delta d$$

Δd : deflection

D : spring constant



approaching
the surface

leaving
the surface

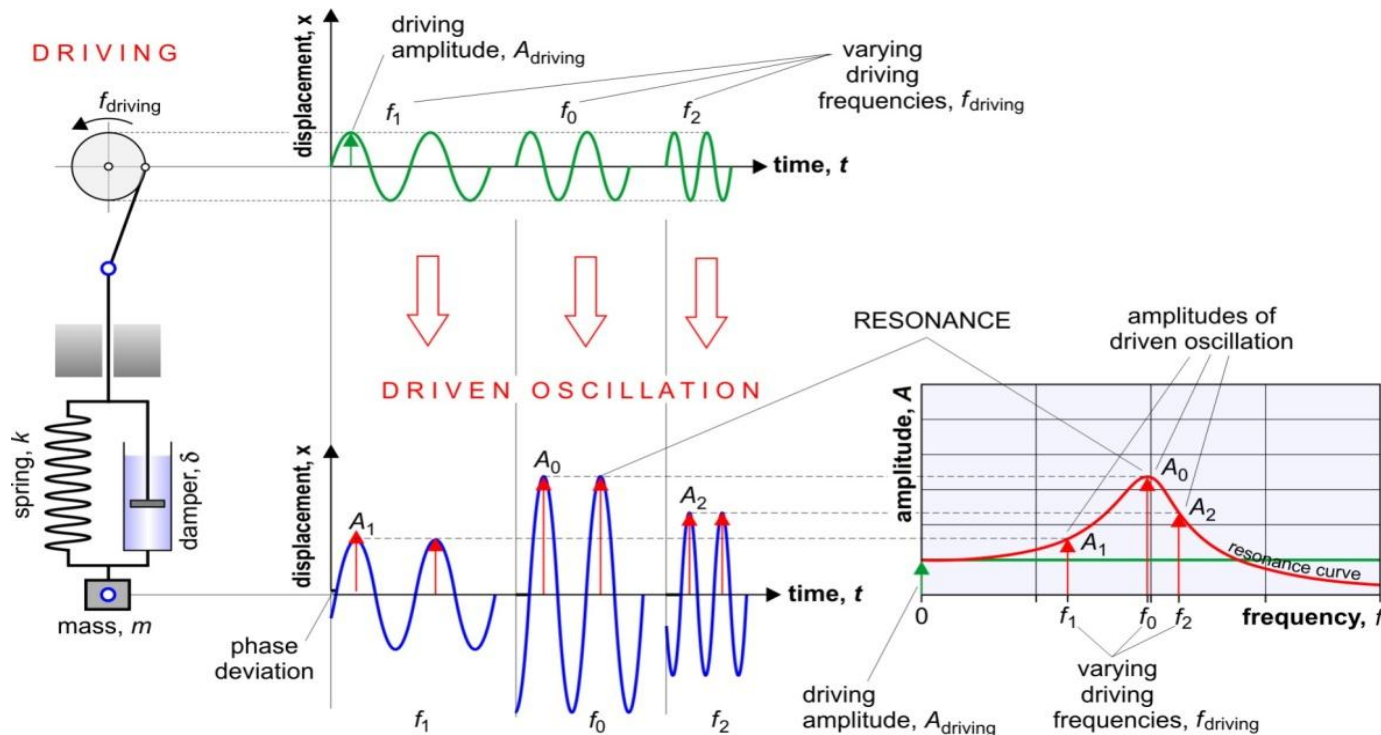
Working principle of AFM 1 contact mode

<http://personal.ph.surrey.ac.uk/~phs1ad/MAT/MAT/Scanning%20Probe%20Micorscopies/Atomic%20Force%20Microscopy/force-displacement%5B1%5D.swf>

Working principle of AFM 2

oscillating mode

RESONANCE: a driven oscillation occurring when the oscillatory system is exposed to a driving force with a frequency close to its eigenfrequency. Amplitudes may become extremely large.



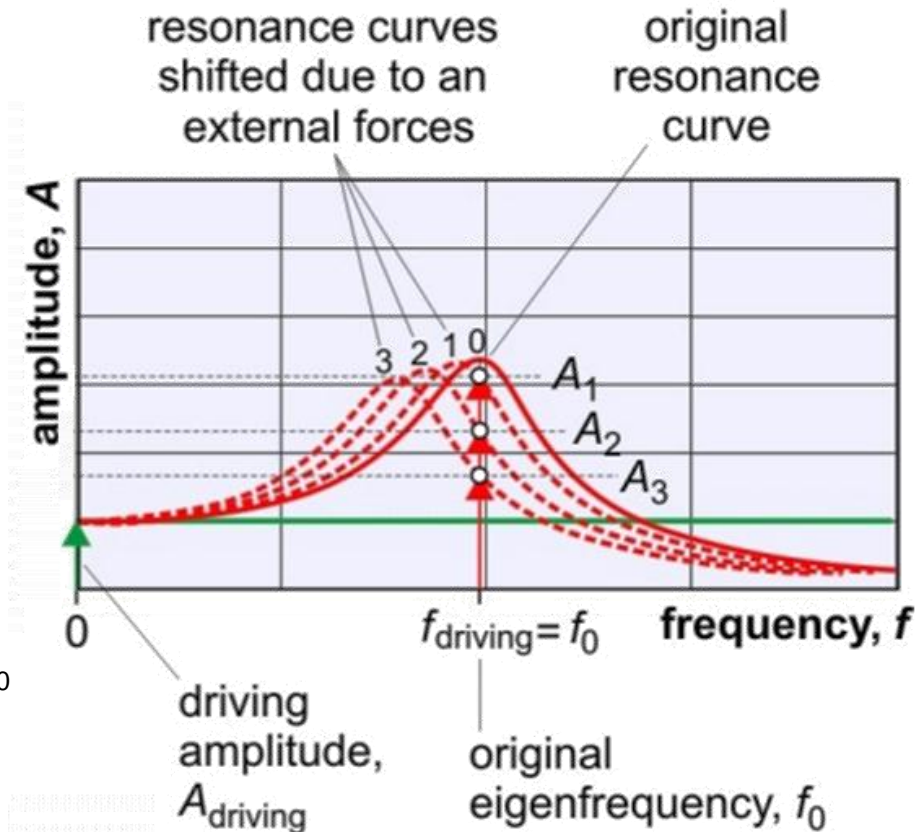
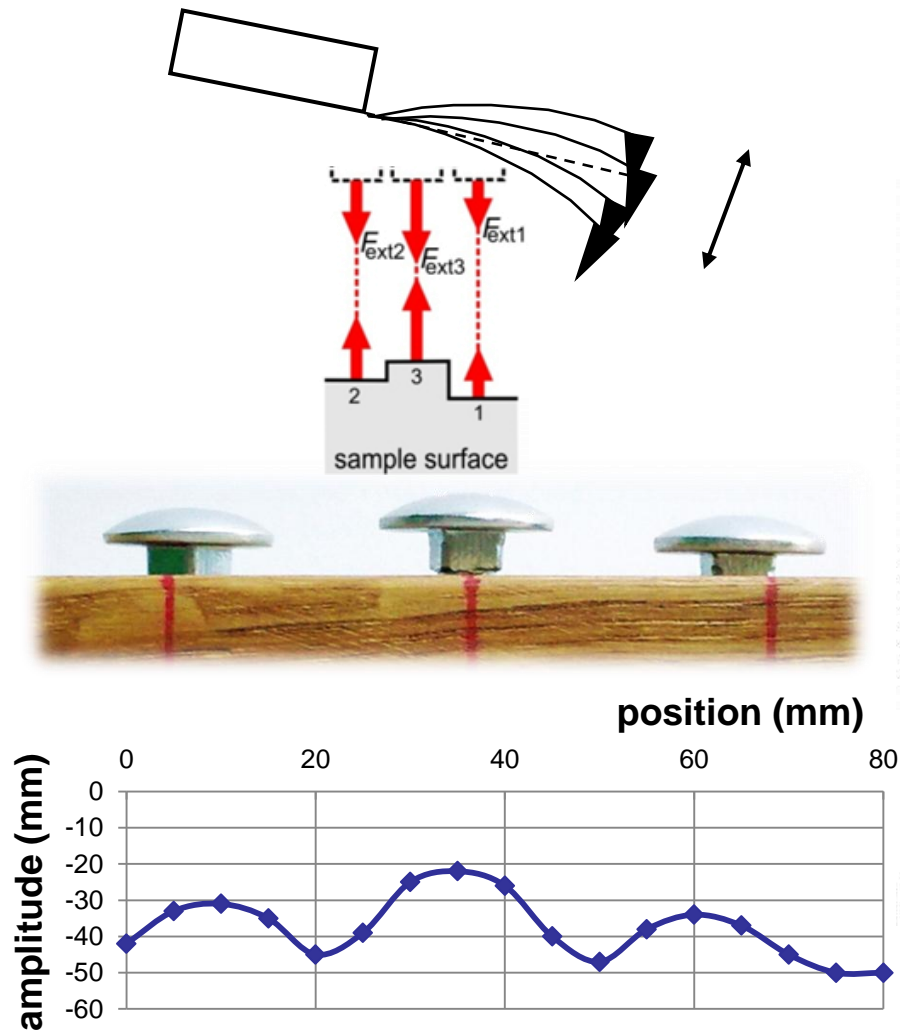
resonance in medical sciences:

- light absorption



- MRI: magnetic resonance imaging
- FRET: fluorescence resonance energy transfer

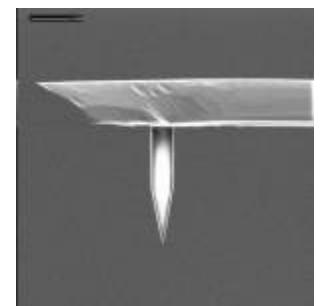
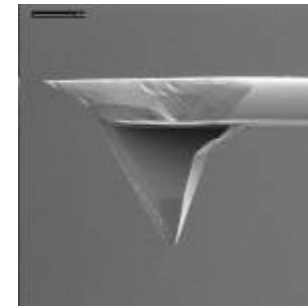
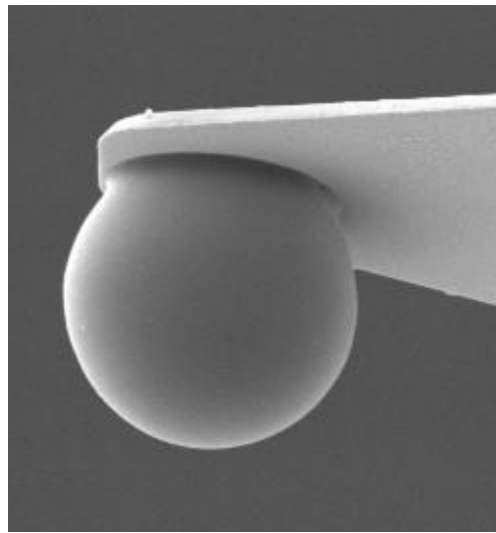
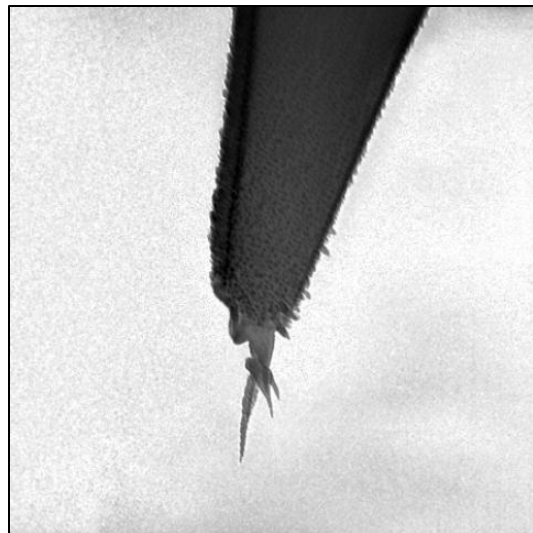
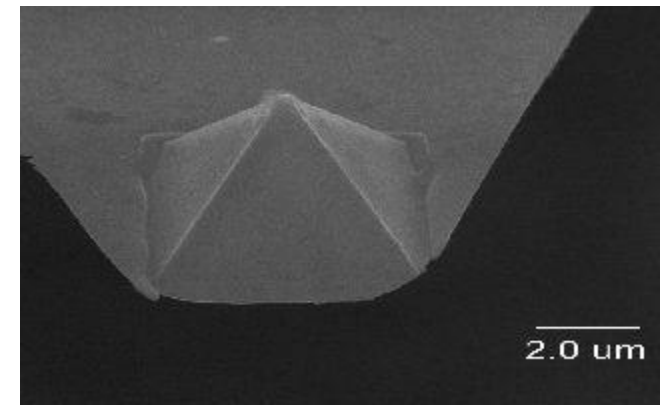
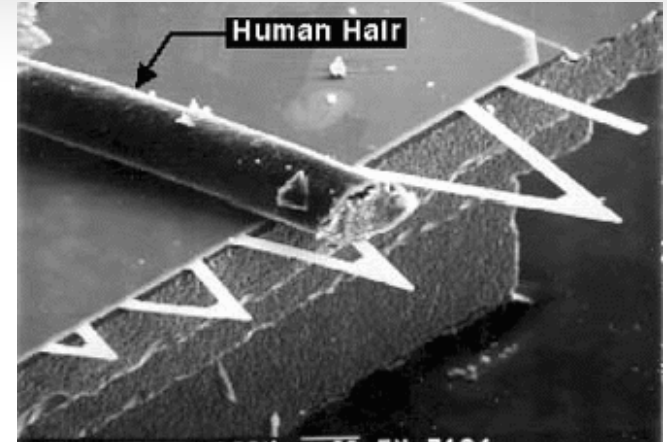
Working principle of AFM 2 oscillating mode



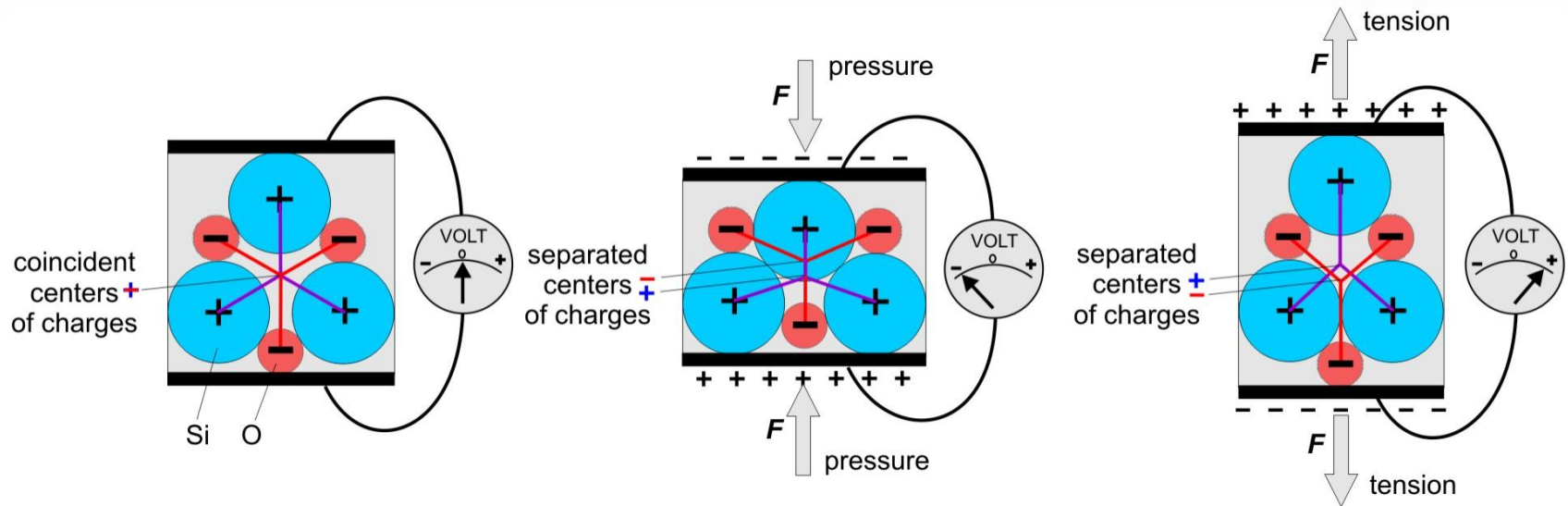
$$f_0 = \frac{1}{2\pi} \sqrt{\frac{D}{m}}$$

Cantilevers

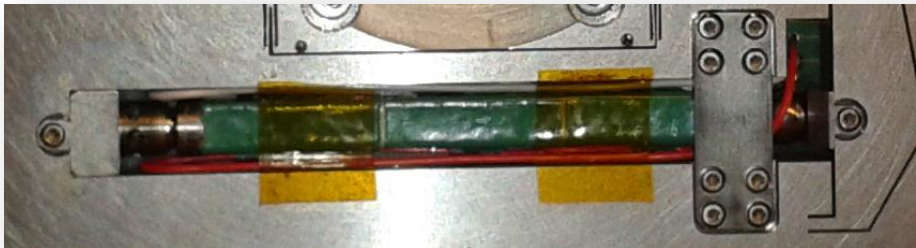
- material: silicon nitride (might be functionalized)
- tip radius: 0,1 nm- 100 μm
- spring constant $\sim 0,1\text{-}10\text{ N/m}$
- $f_0 \sim 50\text{-}500\text{ kHz}$



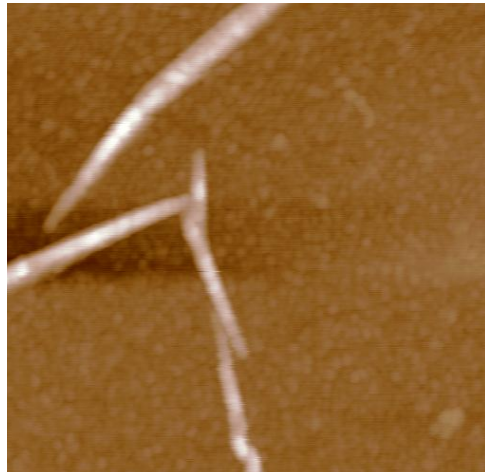
Principle of scanning: piezoelectricity



- **direct piezoelectric effect: deformation \rightarrow voltage**
- **inverse piezoelectric effect: voltage \rightarrow deformation**
- **X, Y, Z axes piezo: e.g. 150 V \rightarrow 40 μ m**



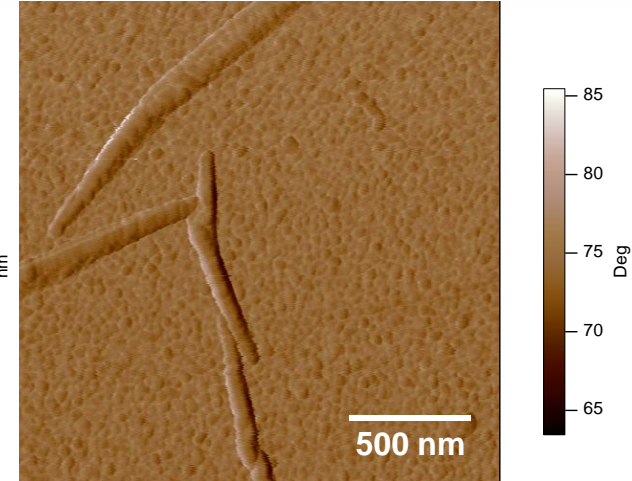
Imaging, resolution




height contrast

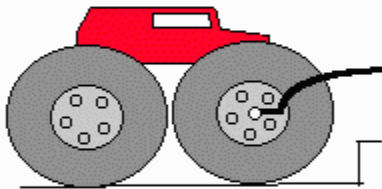


amplitude contrast

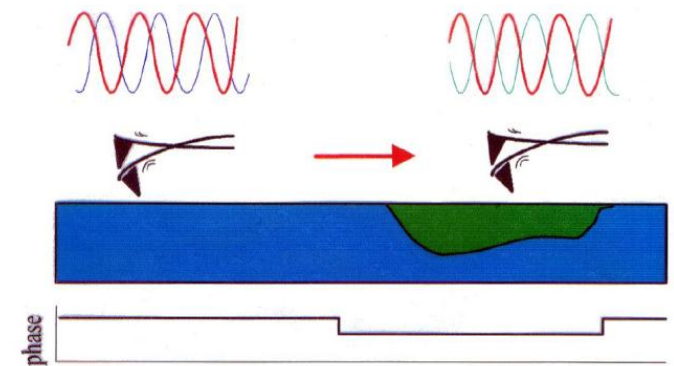
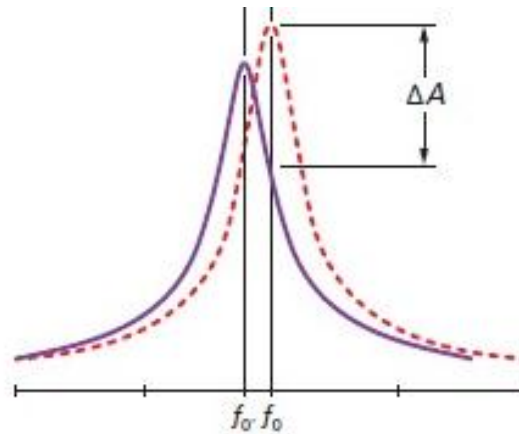


phase contrast

This profile... 
can be made with this monster...



or with this bug!

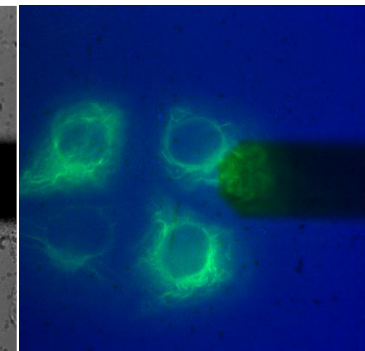
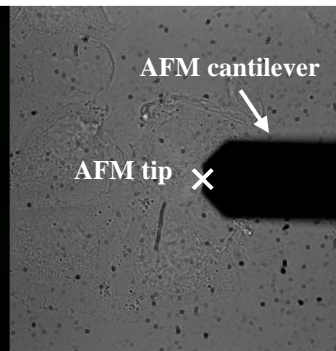
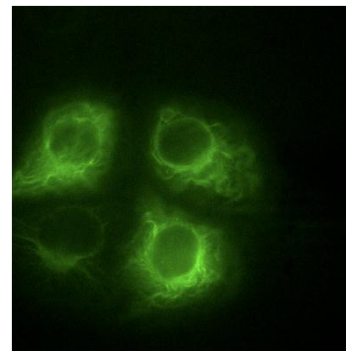
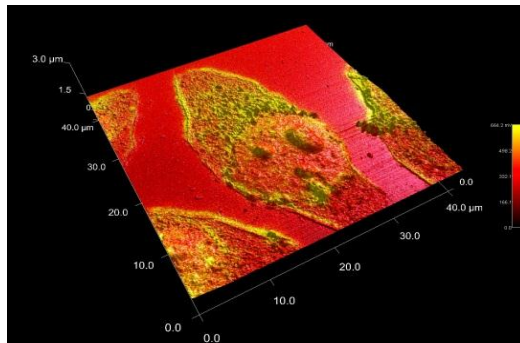
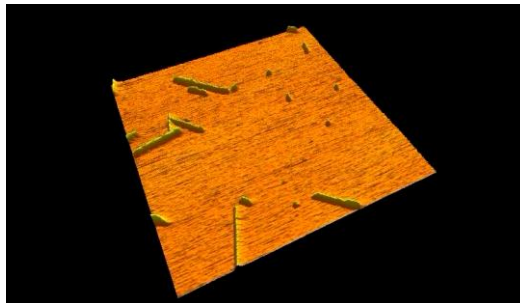
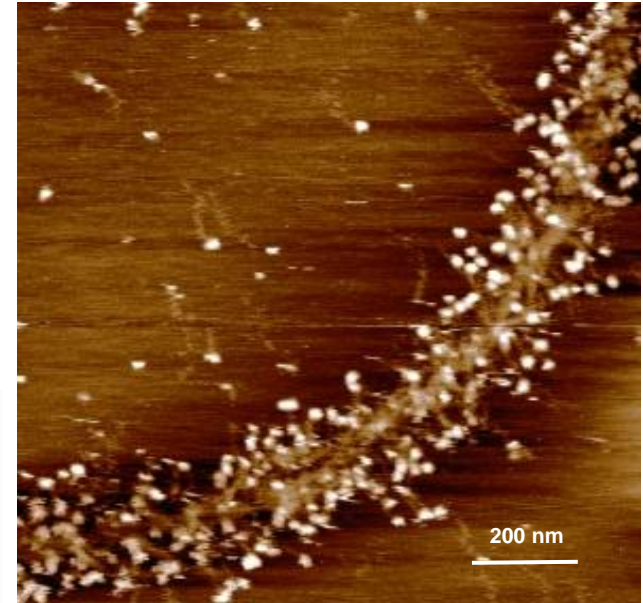
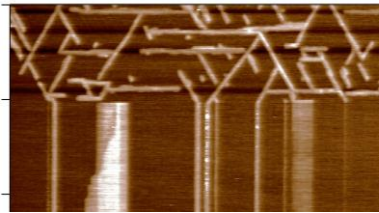
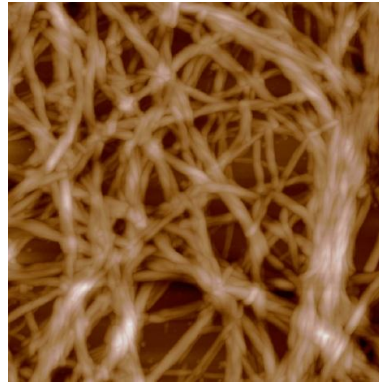
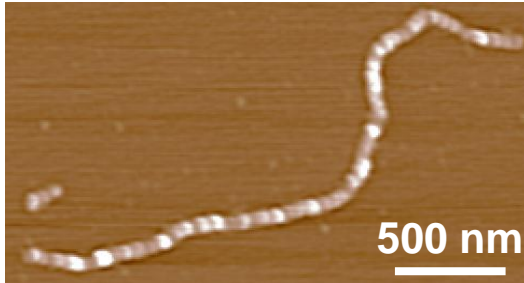


sensitive to viscoelasticity

Imaging artifacts

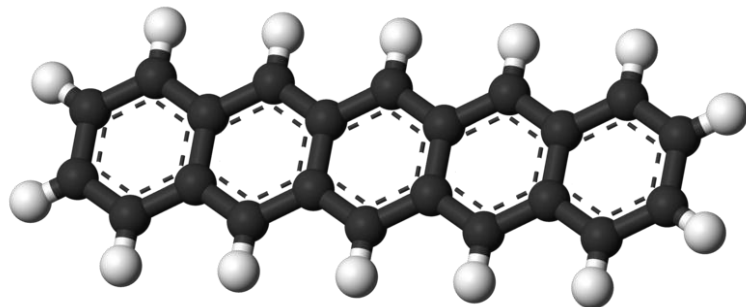
<http://personal.ph.surrey.ac.uk/~phs1ad/MAT/MAT/Scanning%20Probe%20Micorscopies/Atomic%20Force%20Microscopy/sharp%2520v%2520blunt%2520tip%5B1%5D.swf>

Images were born in our lab...

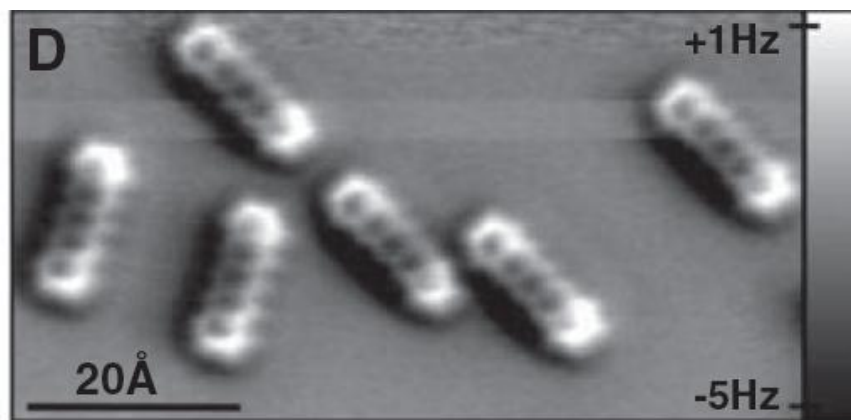
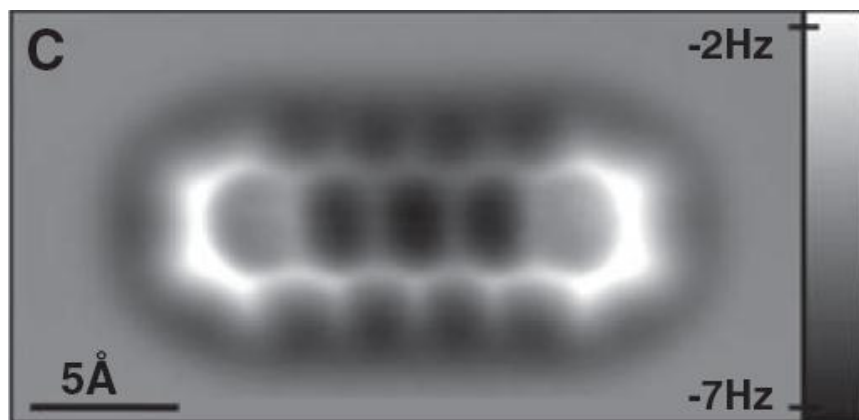


Pentacene molecule

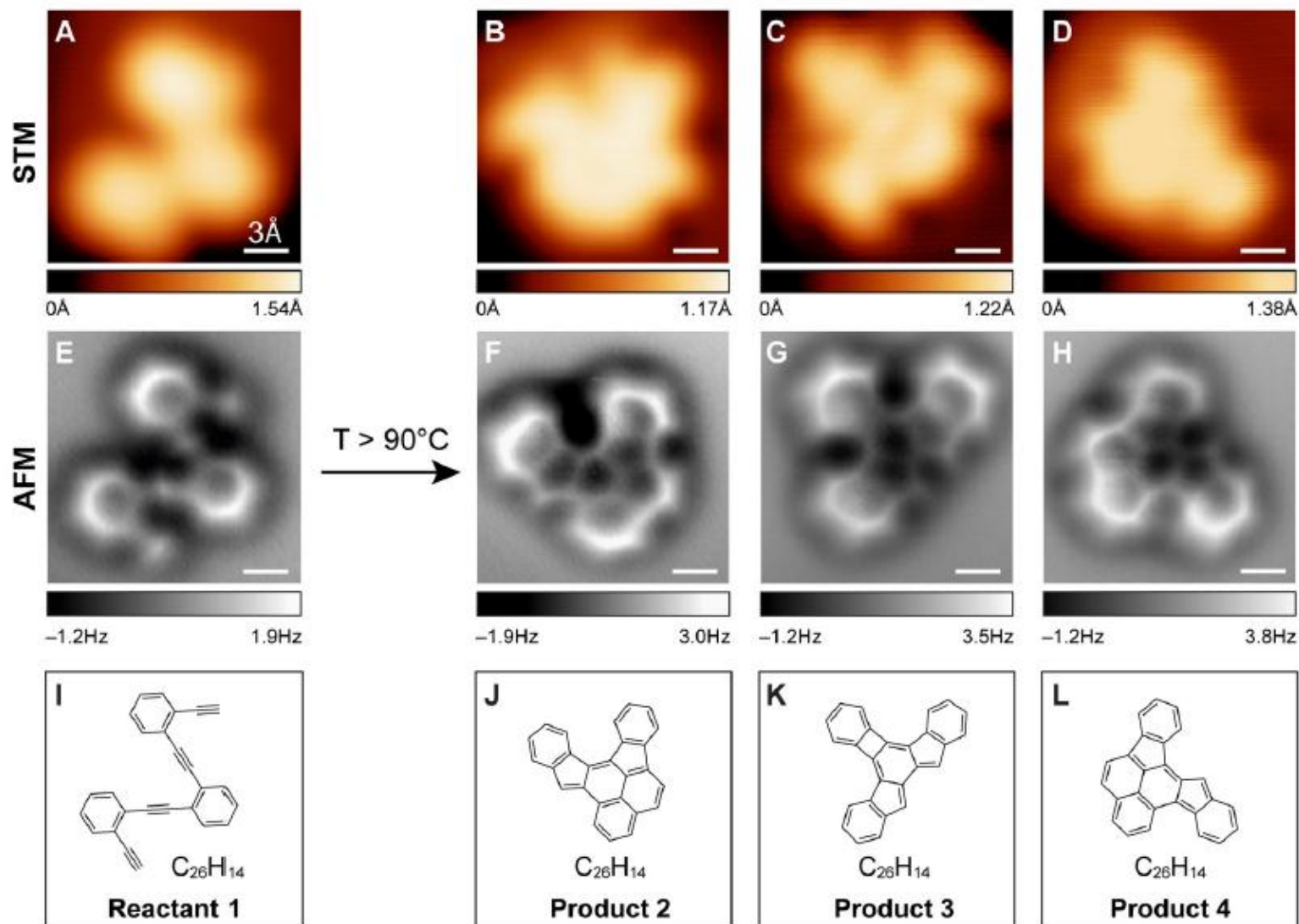
STM



AFM (tip covered with CO)



Visualizing chemical reactions

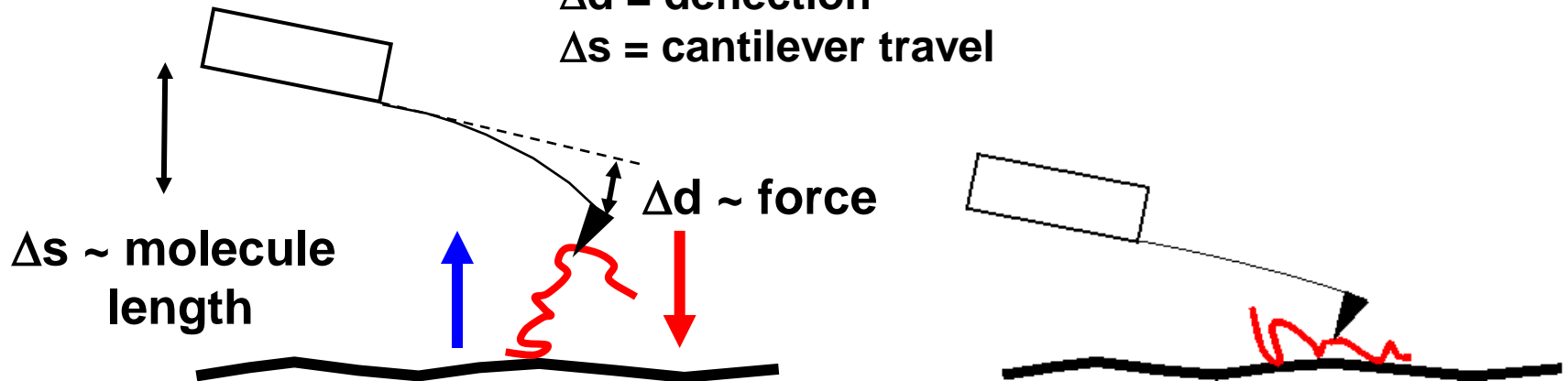


Force measurement with AFM

$$F = \text{force} = D \Delta d$$

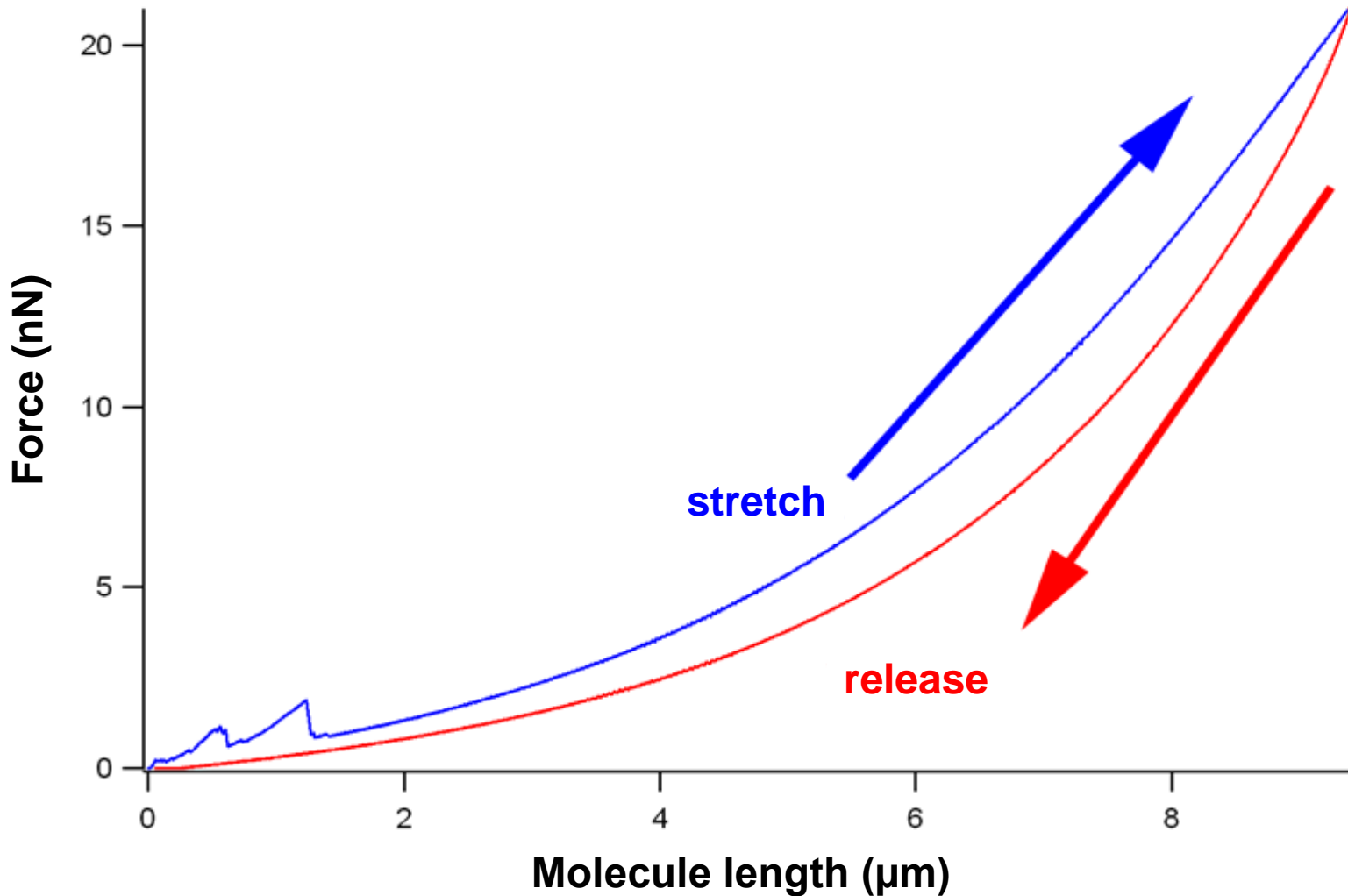
Δd = deflection

Δs = cantilever travel

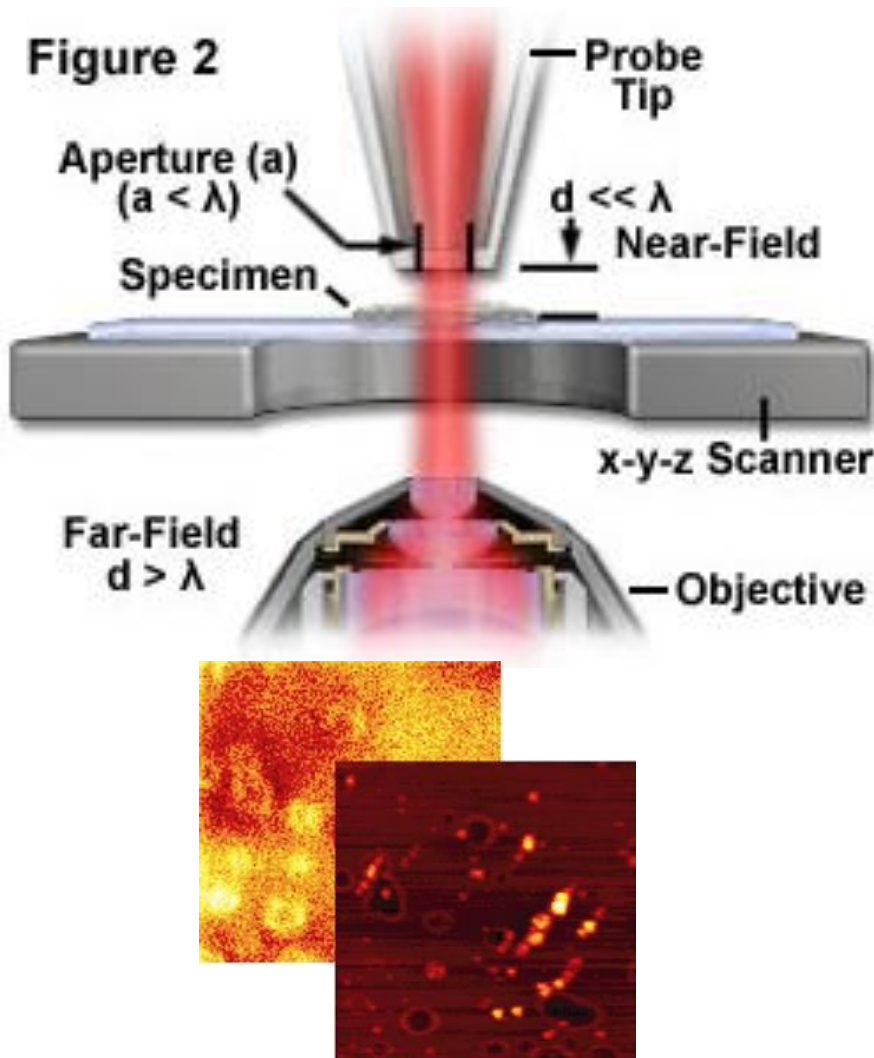


Type of Force	Example	Rupture Force
Breaking of a covalent bond	C-C	≈ 1600 pN
Breaking of a noncovalent bond	Biotin/streptavidin	≈ 160 pN
Breaking of a weak bond	Hydrogen bond	≈ 4 pN
Stretching dsDNA	to 50% relative extension	0.1 pN
Developed by a molecular motor	Kinesin walking on microtubule	5 pN (max)

Stretch-release curve measured with AFM



NSOM (Near Field Scanning Optical Microscopy)



- optical fiber (probe)
- illumination by laser (excitation)
- beam diameter: $a < \lambda$
- close to the probe tip („near-field”): no diffraction
- limit of resolution: 30-100 nm
- detector (commercial objective lens) in the „far-field”

Family tree of scanning probe microscopes

Scanning Thermal Microscopy (SThM)

Scanning Capacitance Microscopy (SCM)

Near Field Scanning Optical Microscopy (NSOM)

Scanning Force Microscopy (SFM)

Atomic Force Microscopy (AFM)

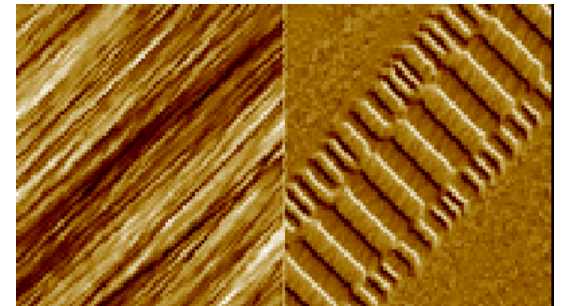
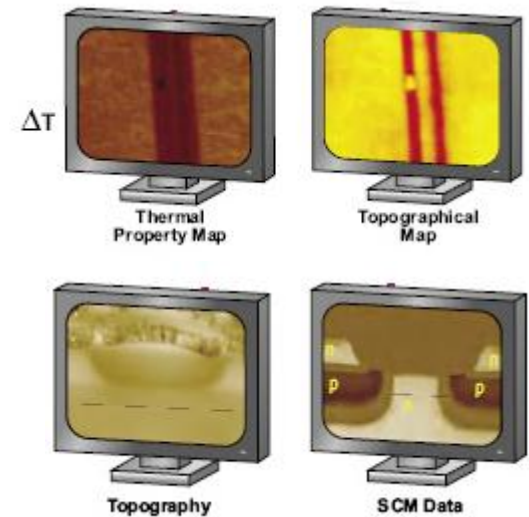
Lateral Force Microscopy (LFM)

Electrical Force Microscopy (EFM)

Chemical Force Microscopy (CFM)

Magnetic Force Microscopy (MFM)

Scanning Tunneling Microscopy (STM)



MFM: harddisk tracks

Thank YOU for your attention!

